

EQRD13J2J-53.125M

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REGULATORY COMPLIANCE (Data Sheet downloaded on Dec 5, 2019)


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ITEM DESCRIPTION

Quartz Crystal Clock Oscillators XO (SPXO) LVPECL (PECL) 3.3Vdc 6 Pad 5.0mm x 7.0mm Ceramic Surface Mount (SMD) 53.125MHz ± 100 ppm over -40°C to +85°C

ELECTRICAL SPECIFICATIONS

Nominal Frequency	53.125MHz
Frequency Tolerance/Stability	± 100 ppm Maximum over -40°C to +85°C (Inclusive of all conditions: Calibration Tolerance (at 25°C), Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration)
Aging at 25°C	± 3 ppm Maximum First Year
Supply Voltage	3.3Vdc $\pm 5\%$
Input Current	50mA Maximum
Output Voltage Logic High (Voh)	Vdd-1.025Vdc Minimum, 2.35Vdc Typical, Vdd-0.88Vdc Maximum
Output Voltage Logic Low (Vol)	Vdd-1.81Vdc Minimum, 1.60Vdc Typical, Vdd-1.62Vdc Maximum
Rise/Fall Time	400pSec Maximum (Measured at 20% to 80% of Waveform)
Duty Cycle	50 ± 5 (%) (Measured at 50% of Waveform)
Load Drive Capability	50 Ohms into Vdd-2.0Vdc
Output Logic Type	LVPECL
Phase Noise	All Values are Typical -50dBc/Hz at 10Hz Offset -82dBc/Hz at 100Hz Offset -116dBc/Hz at 1kHz Offset -138dBc/Hz at 10kHz Offset -144dBc/Hz at 100kHz Offset -149dBc/Hz at 1MHz Offset -155dBc/Hz at 10MHz Offset -155dBc/Hz at 20MHz Offset
Output Control Function	Standby (on Pad 1)
Output Control Input Voltage Logic High (Vih)	70% of Vdd Minimum or No Connect to Enable Output and Complementary Output
Output Control Input Voltage Logic Low (Vil)	30% of Vdd Maximum to Disable Output and Complementary Output (High Impedance)
Standby Output Enable Time	10mSec Maximum
Standby Output Disable Time	200nSec Maximum
Standby Current	10 μ A Maximum (Without Load)
RMS Phase Jitter	450fSec Maximum (Fj=12kHz to 20MHz (Random))
Period Jitter (Deterministic)	0.2pSec Typical
Period Jitter (Random)	1.0pSec Typical
Period Jitter (One Sigma)	1.5pSec Typical
Period Jitter (tp-p)	40pSec Maximum
Start Up Time	10mSec Maximum
Storage Temperature Range	-55°C to +125°C

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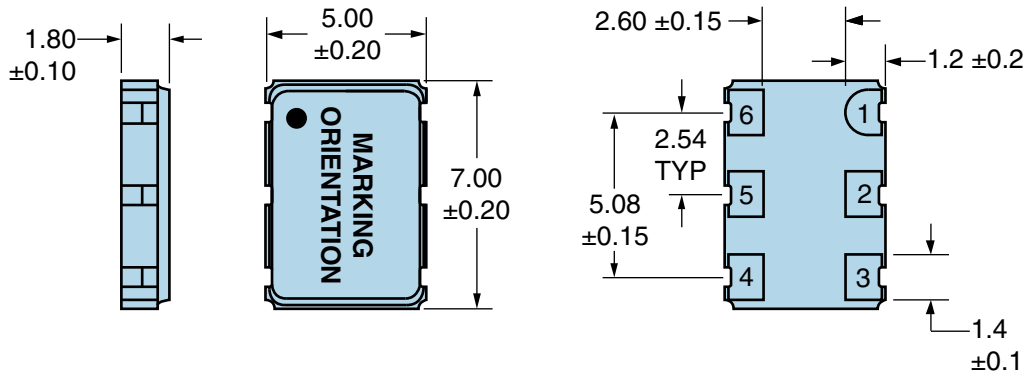
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ENVIRONMENTAL & MECHANICAL SPECIFICATIONS

ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500V
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Flammability	UL94-V0
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Mechanical Shock	MIL-STD-883, Method 2002, Condition B
Moisture Resistance	MIL-STD-883, Method 1004
Moisture Sensitivity	J-STD-020, MSL 1
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K
Resistance to Solvents	MIL-STD-202, Method 215
Solderability	MIL-STD-883, Method 2003
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A

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MECHANICAL DIMENSIONS (all dimensions in millimeters)

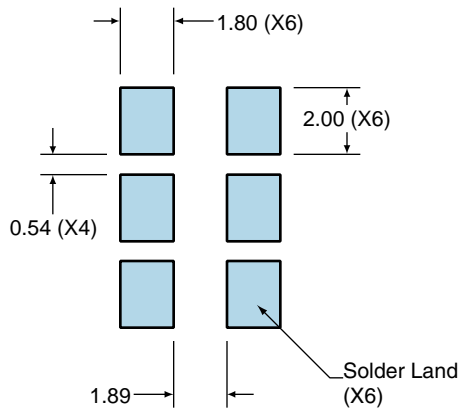


PIN	CONNECTION
1	Standby
2	No Connect
3	Case Ground
4	Output
5	Complementary Output
6	Supply Voltage

LINE	MARKING
1	ECLIPTEK
2	53.125M
3	XXXXX XXXXX=Ecliptek Manufacturing Identifier

Suggested Solder Pad Layout

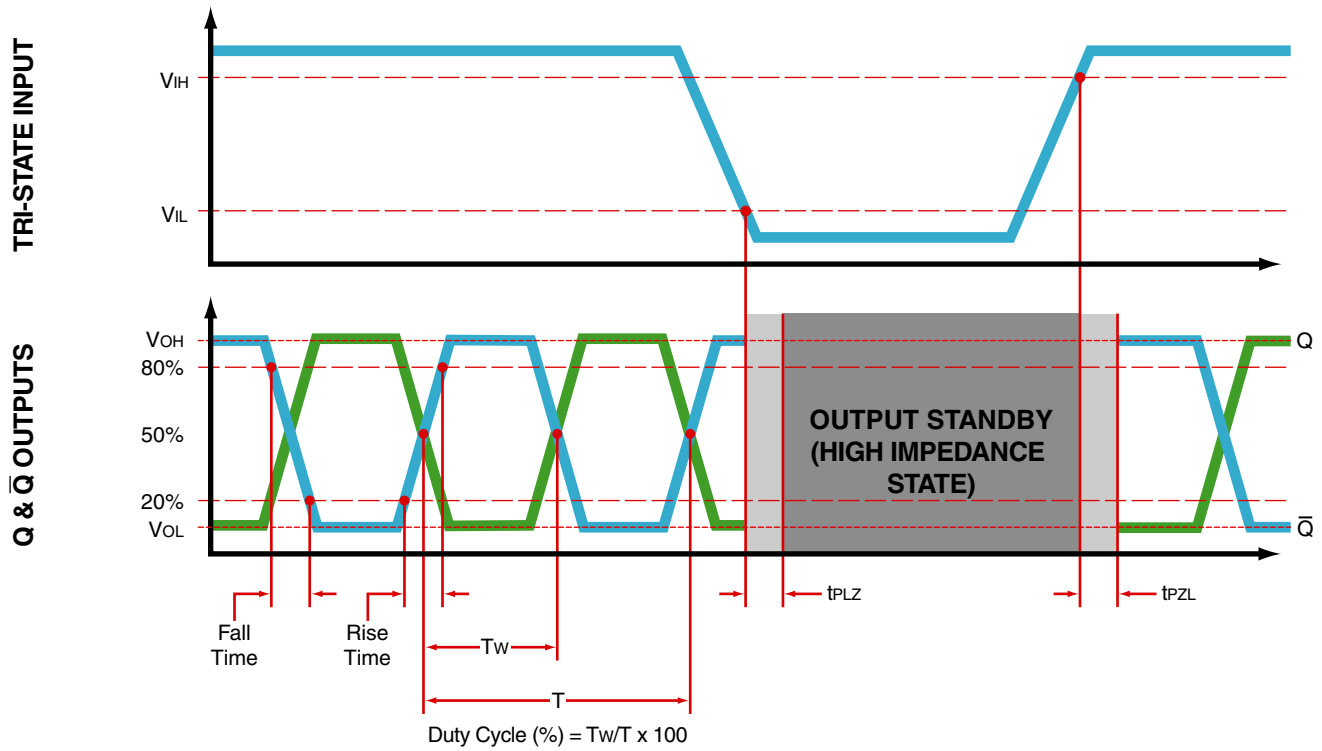
All Dimensions in Millimeters



All Tolerances are ± 0.1

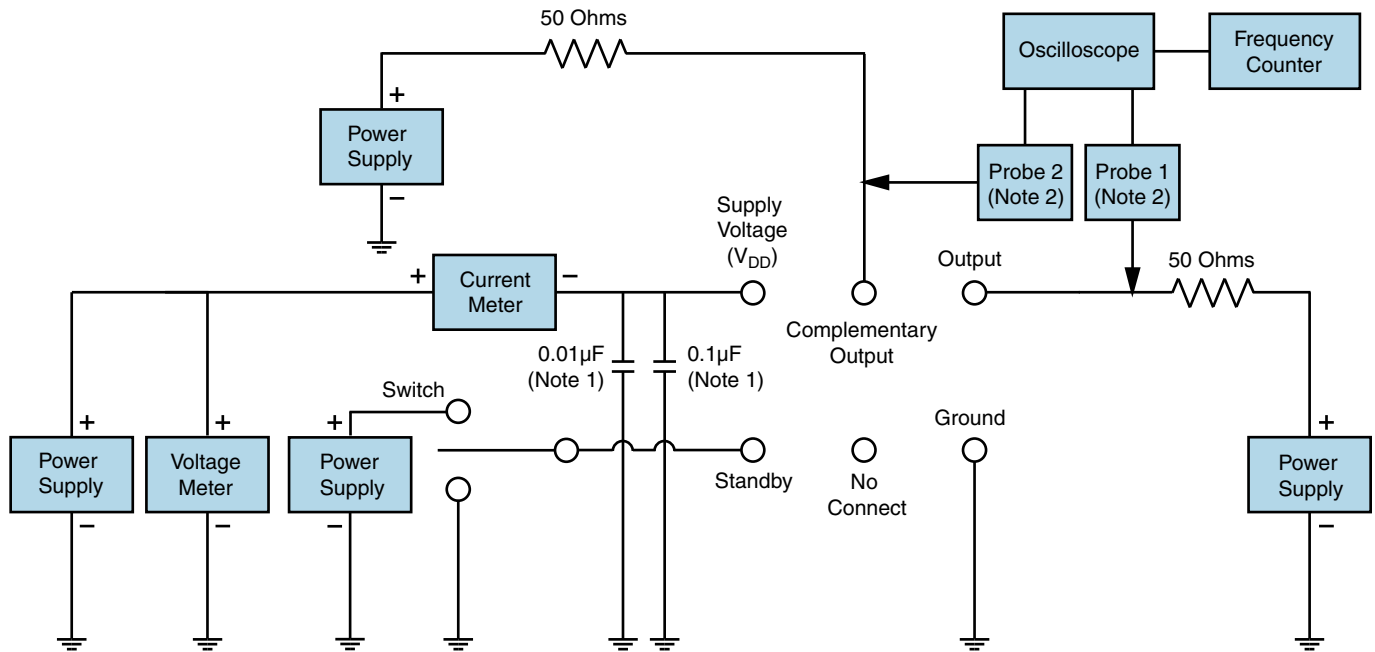
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OUTPUT WAVEFORM & TIMING DIAGRAM



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Test Circuit for Standby (Pad 1) and Complementary Output



Note 1: An external 0.01µF ceramic bypass capacitor in parallel with a 0.1µF high frequency ceramic bypass capacitor close (less than 2mm) to the package ground and supply voltage pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>500MHz) passive probe is recommended.

Note 3: Test circuit PCB traces need to be designed for a characteristic line impedance of 50 ohms.

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Recommended Solder Reflow Methods



High Temperature Infrared/Convection

T_s MAX to T_L (Ramp-up Rate)	3°C/Second Maximum
Preheat	
- Temperature Minimum (T_s MIN)	150°C
- Temperature Typical (T_s TYP)	175°C
- Temperature Maximum (T_s MAX)	200°C
- Time (t_s MIN)	60 - 180 Seconds
Ramp-up Rate (T_L to T_P)	3°C/Second Maximum
Time Maintained Above:	
- Temperature (T_L)	217°C
- Time (t_L)	60 - 150 Seconds
Peak Temperature (T_P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T_P Target)	250°C +0/-5°C
Time within 5°C of actual peak (t_p)	20 - 40 Seconds
Ramp-down Rate	6°C/Second Maximum
Time 25°C to Peak Temperature (t)	8 Minutes Maximum
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

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Recommended Solder Reflow Methods



Low Temperature Infrared/Convection 240°C

T_s MAX to T_L (Ramp-up Rate)	5°C/Second Maximum
Preheat	
- Temperature Minimum (T_s MIN)	N/A
- Temperature Typical (T_s TYP)	150°C
- Temperature Maximum (T_s MAX)	N/A
- Time (t_s MIN)	60 - 120 Seconds
Ramp-up Rate (T_L to T_P)	5°C/Second Maximum
Time Maintained Above:	
- Temperature (T_L)	150°C
- Time (t_L)	200 Seconds Maximum
Peak Temperature (T_P)	240°C Maximum
Target Peak Temperature (T_P Target)	240°C Maximum 2 Times / 230°C Maximum 1 Time
Time within 5°C of actual peak (t_p)	10 Seconds Maximum 2 Times / 80 Seconds Maximum 1 Time
Ramp-down Rate	5°C/Second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

Low Temperature Manual Soldering

185°C Maximum for 10 Seconds Maximum, 2 times Maximum. (Temperatures listed are applied to body of device.)

High Temperature Manual Soldering

260°C Maximum for 5 Seconds Maximum, 2 times Maximum. (Temperatures listed are applied to body of device.)